



# Synchronous Buck NexFET™ Power Block II

#### **FEATURES**

- Half-Bridge Power Block
- 90% system Efficiency at 20A
- Up To 25A Operation
- High Density 5-mm x 2.5-mm LGA Footprint
- Double Side Cooling Capability
- Ultra Low Profile 0.48-mm MAX
- Optimized for 5V Gate Drive
- Low Switching Losses
- Low Inductance Package
- RoHS Compliant
- Halogen Free
- Pb-Free Terminal Plating

## **APPLICATIONS**

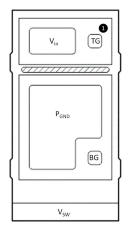
- Synchronous Buck Converters
  - High Current, Low Duty Cycle Applications
- Multiphase Synchronous Buck Converters
- POL DC-DC Converters

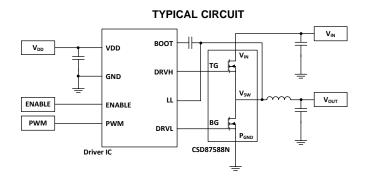
#### **DESCRIPTION**

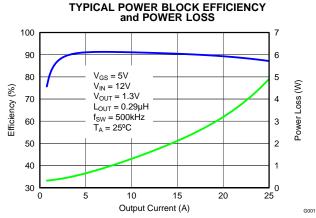
The CSD87588N NexFET™ power block II is a highly optimized design for synchronous buck applications offering high current and high efficiency capability in a small 5-mm × 2.5-mm outline. Optimized for 5V gate drive applications, this product offers an efficient and flexible solution capable of providing a high density power supply when paired with any 5V gate driver from an external controller/driver.

#### **ORDERING INFORMATION**

Device	Package	Media	Qty	Ship
CSD87588N	5 x 2.5 LGA	13-Inch Reel	2500	Tape and Reel







W

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.





These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

#### **ABSOLUTE MAXIMUM RATINGS**

 $T_A = 25$ °C (unless otherwise noted) (1)

Parameter	Conditions	V	ALUE	UNIT
		MIN	MAX	
	V <sub>IN</sub> to P <sub>GND</sub>		30	
	V <sub>SW</sub> to P <sub>GND</sub>		30	
$ \begin{array}{c c} \text{Voltage range} & V_{SW} \text{ to } P_{GND} \text{ (10 ns)} \\ \hline T_{G} \text{ to } V_{SW} \\ \hline B_{G} \text{ to } P_{GND} \\ \\ \text{Pulsed Current Rating, } I_{DM}^{(2)} \end{array} $	V <sub>SW</sub> to P <sub>GND</sub> (10 ns)		32	V
	$T_G$ to $V_{SW}$	-20	20	
	B <sub>G</sub> to P <sub>GND</sub>	-20	20	
Pulsed Current Rating	, I <sub>DM</sub> <sup>(2)</sup>		50	А
Power Dissipation, P <sub>D</sub>	(3)		6	W
Sync FET, I <sub>D</sub> = 45A, L = 0.1mH			101	1
Avalanche Energy E <sub>AS</sub>	Control FET, I <sub>D</sub> =26A, L = 0.1mH		34	mJ
Operating Junction and	d Storage Temperature Range, T <sub>J</sub> , T <sub>STG</sub>	-55	150	°C

<sup>(1)</sup> Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated is not implied. Exposure to absolutemaximum-rated conditions for extended periods may affect device reliability.

#### RECOMMENDED OPERATING CONDITIONS

 $T_A = 25^{\circ}$  (unless otherwise noted)

Parameter	Conditions	MIN	MAX	UNIT
Gate Drive Voltage, V <sub>GS</sub>		4.5	16	V
Input Supply Voltage, V <sub>IN</sub>			24	V
Switching Frequency, f <sub>SW</sub>	$C_{BST} = 0.1 \mu F \text{ (min)}$	200	1500	kHz
Operating Current	No Airflow		25	Α
	With Airflow		30	Α
	With Airflow + Heat Sink		35	Α
Operating Temperature, T <sub>J</sub>			125	°C

# POWER BLOCK PERFORMANCE

 $T_A = 25^{\circ}$  (unless otherwise noted)

Parameter	Conditions	MIN	TYP	MAX	UNIT
Power Loss, P <sub>LOSS</sub> <sup>(1)</sup>	$V_{IN} = 12V, V_{GS} = 5V, \ V_{OUT} = 1.3V, I_{OUT} = 15A, \ f_{SW} = 500kHz, \ L_{OUT} = 0.29\mu H, T_J = 25^{\circ}C$		2.1		W
V <sub>IN</sub> Quiescent Current, I <sub>QVIN</sub>	$T_G$ to $T_{GR} = 0V$ $B_G$ to $P_{GND} = 0V$		10		μΑ

Measurement made with six 10μF (TDK C3216X5R1C106KT or equivalent) ceramic capacitors placed across V<sub>IN</sub> to P<sub>GND</sub> pins and using a high current 5V driver IC.

Pulse Duration ≤50 μS. Duty cycle ≤0.01.

<sup>(3)</sup> Device mounted on FR4 material with 1-inch2 (6.45-cm2) Cu.



## THERMAL INFORMATION

 $T_A = 25$ °C (unless otherwise stated)

	THERMAL METRIC	MIN	TYP	MAX	UNIT
D	Junction to ambient thermal resistance (Min Cu) (1)			170	
$R_{\theta JA}$	Junction to ambient thermal resistance (Max Cu) (2)(1)			70	°C/W
Б	Junction to case thermal resistance (Top of package) (1)			3.7	C/VV
$R_{\theta JC}$	Junction to case thermal resistance (P <sub>GND</sub> Pin) <sup>(1)</sup>			1.25	

<sup>(1)</sup> R<sub>BJC</sub> is determined with the device mounted on a 1-inch² (6.45-cm²), 2 oz. (0.071-mm thick) Cu pad on a 1.5-inch × 1.5-inch (3.81-cm × 3.81-cm), 0.06-inch (1.52-mm) thick FR4 board. R<sub>BJC</sub> is specified by design while R<sub>BJA</sub> is determined by the user's board design.

<sup>(2)</sup> Device mounted on FR4 material with 1-inch<sup>2</sup> (6.45-cm<sup>2</sup>) Cu.

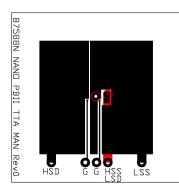


#### **ELECTRICAL CHARACTERISTICS**

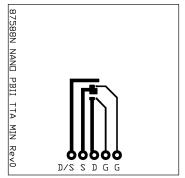
 $T_A = 25$ °C (unless otherwise stated)

	DADAMETER	TEGT CONDITIONS	Q1 C	ontrol FE	T	Q2 Sync FET			
	PARAMETER	TEST CONDITIONS	TYP	MAX	MIN	TYP	MAX	UNIT	
Static Cha	aracteristics								
BV <sub>DSS</sub>	Drain to Source Voltage	$V_{GS} = 0V, I_{DS} = 250\mu A$	30			30			V
I <sub>DSS</sub>	Drain to Source Leakage Current	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 24V			1			1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	V <sub>DS</sub> = 0V, V <sub>GS</sub> = 20			100			100	nA
V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{DS} = V_{GS}, I_{DS} = 250 \mu A$	1.1		1.9	1.1		1.9	V
D	Drain to Source On	V <sub>GS</sub> = 4.5V, I <sub>DS</sub> = 15A		10.4	12.5		3.5	4.2	0
R <sub>DS(on)</sub>	Resistance	V <sub>GS</sub> = 10V, I <sub>DS</sub> = 15A		8.0	9.6		2.9	3.5	mΩ
9 <sub>fs</sub>	Transconductance	V <sub>DS</sub> = 10V, I <sub>DS</sub> = 15A		43			93		S
Dynamic	Characteristics				·				
C <sub>ISS</sub>	Input Capacitance (1)			566	736		2310	3000	pF
Coss	Output Capacitance (1)	$V_{GS} = 0V, V_{DS} = 15V,$		341	444		682	887	pF
C <sub>RSS</sub>	Reverse Transfer Capacitance <sup>(1)</sup>	f = 1MHz		10.3	13.4		62	80.4	pF
R <sub>G</sub>	Series Gate Resistance (1)			1.2	2.4		1.1	2.2	Ω
Qg	Gate Charge Total (4.5V)			3.2	4.1		13.7	17.9	nC
Q <sub>gd</sub>	Gate Charge - Gate to Drain	V <sub>DS</sub> = 15V,		0.7			4.3		nC
Q <sub>gs</sub>	Gate Charge - Gate to Source	I <sub>DS</sub> = 15A		1.4			4.3		nC
Q <sub>g(th)</sub>	Gate Charge at Vth			0.8			2.8		nC
Q <sub>OSS</sub>	Output Charge	$V_{DD} = 12V, V_{GS} = 0V$		7.0			18.6		nC
t <sub>d(on)</sub>	Turn On Delay Time			7.3			12.1		ns
t <sub>r</sub>	Rise Time	$V_{DS} = 15V, V_{GS} = 4.5V,$		31.6			36.7		ns
t <sub>d(off)</sub>	Turn Off Delay Time	$I_{DS} = 15A$ , $R_G = 2\Omega$		10.2			20.1		ns
t <sub>f</sub>	Fall Time			5.0			6.3		ns
Diode Ch	aracteristics								
V <sub>SD</sub>	Diode Forward Voltage	$I_{DS} = 15A, V_{GS} = 0V$		0.85			0.78		V
Q <sub>rr</sub>	Reverse Recovery Charge	$V_{dd} = 15V, I_F = 15A,$		12.5			26.7		nC
t <sub>rr</sub>	Reverse Recovery Time	di/dt = 300A/µs		16			23		ns

# (1) Specified by design



Max  $R_{\theta JA} = 70^{\circ}\text{C/W}$  when mounted on 1 inch² (6.45 cm²) of 2-oz. (0.071-mm thick) Cu.

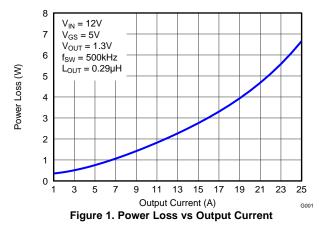


Max  $R_{\theta JA} = 170^{\circ} C/W$  when mounted on minimum pad area of 2-oz. (0.071-mm thick) Cu.



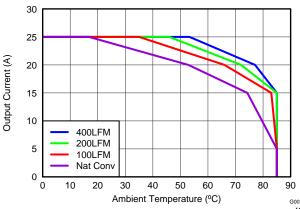
#### TYPICAL POWER BLOCK DEVICE CHARACTERISTICS

 $T_J = 125$ °C, unless stated otherwise.



1.1  $V_{IN} = 12V$  $V_{GS} = 5V$  $V_{OUT} = 1.3V$ Power Loss, Normalized  $f_{SW} = 500kHz$ 0.9  $L_{OUT} = 0.29 \mu H$ 0.8 0.7 0.6 0.5 -50 -25 0 25 50 75 100 125 150 Junction Temperature (°C)





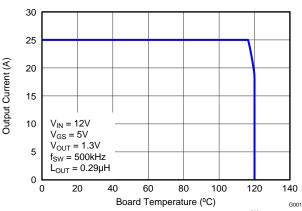
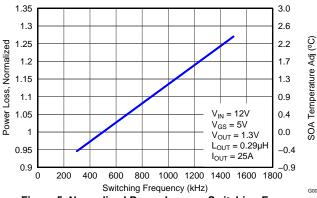


Figure 3. Safe Operating Area – PCB Horizontal Mount (1)

Figure 4. Typical Safe Operating Area<sup>(1)</sup>

(1) The Typical Power Block System Characteristic curves are based on measurements made on a PCB design with dimensions of 4.0" (W) × 3.5" (L) x 0.062" (H) and 6 copper layers of 1 oz. copper thickness. See Application Section for detailed explanation.



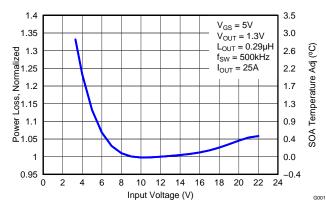


Figure 5. Normalized Power Loss vs Switching Frequency

Figure 6. Normalized Power Loss vs Input Voltage



# TYPICAL POWER BLOCK DEVICE CHARACTERISTICS (continued)

 $T_J = 125$ °C, unless stated otherwise.

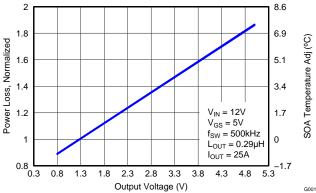


Figure 7. Normalized Power Loss vs. Output Voltage

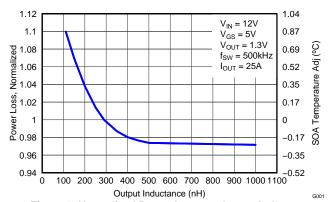


Figure 8. Normalized Power Loss vs. Output Inductance

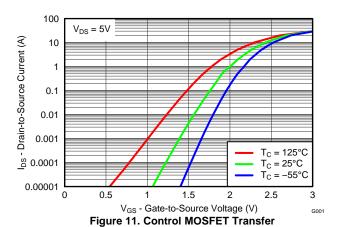


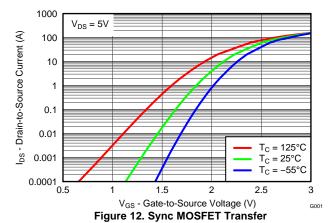
#### TYPICAL POWER BLOCK MOSFET CHARACTERISTICS

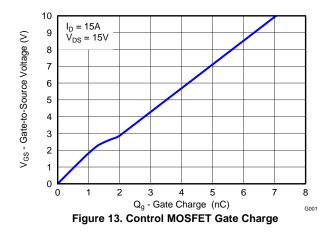
 $T_A = 25$ °C, unless stated otherwise.

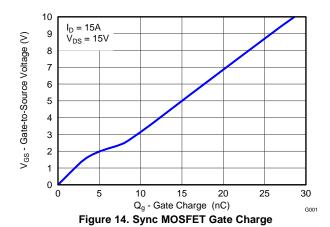


200 180 l<sub>DS</sub> - Drain-to-Source Current (A) 160 140 120 100 80 60  $V_{GS} = 8.0V$ 40  $V_{GS} = 4.5V$ 20  $V_{GS} = 4.0V$ 0 0 0.2 0.4 0.6 0.8 1.2 V<sub>DS</sub> - Drain-to-Source Voltage (V) G001 Figure 10. Sync MOSFET Saturation





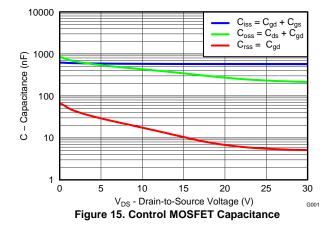




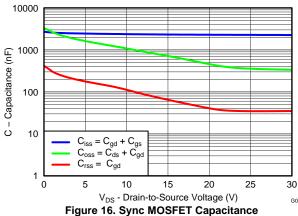


# TYPICAL POWER BLOCK MOSFET CHARACTERISTICS (continued)

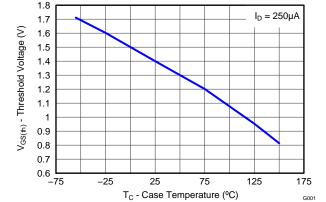
 $T_A = 25$ °C, unless stated otherwise.



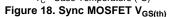
 $C_{rss} = C_{gd}$ 

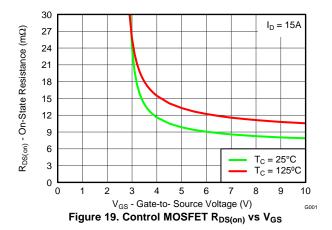


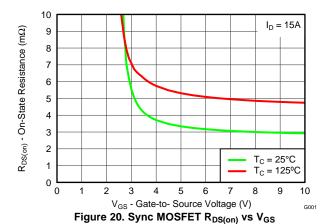
2  $I_D = 250 \mu A$ 1.9 V<sub>GS(th)</sub> - Threshold Voltage (V) 1.8 1.7 1.6 1.5 1.4 1.3 1.2 1.1 1 0.9 8.0 , –75 25 125 175 T<sub>C</sub> - Case Temperature (°C) G001











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# TYPICAL POWER BLOCK MOSFET CHARACTERISTICS (continued)

 $T_A = 25$ °C, unless stated otherwise.

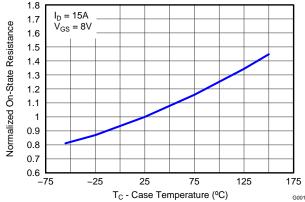


Figure 21. Control MOSFET Normalized R<sub>DS(on)</sub>

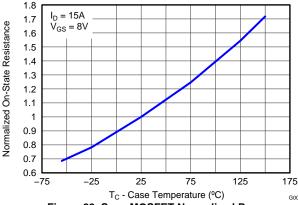
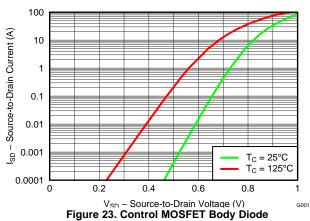


Figure 22. Sync MOSFET Normalized R<sub>DS(on)</sub>



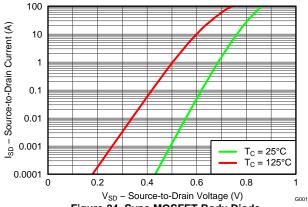


Figure 24. Sync MOSFET Body Diode

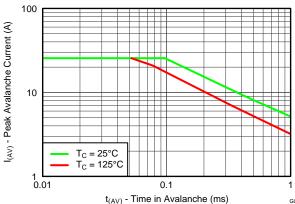


Figure 25. Control MOSFET Unclamped Inductive Switching

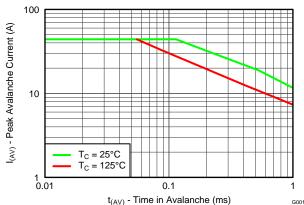


Figure 26. Sync MOSFET Unclamped Inductive Switching



The CSD87588N NexFET™ power block is an optimized design for synchronous buck applications using 5V gate drive. The Control FET and Sync FET silicon are parametrically tuned to yield the lowest power loss and highest system efficiency. As a result, a new rating method is needed which is tailored towards a more systems centric environment. System level performance curves such as Power Loss, Safe Operating Area, and normalized graphs allow engineers to predict the product performance in the actual application.

#### **Power Loss Curves**

MOSFET centric parameters such as  $R_{DS(ON)}$  and  $Q_{gd}$  are needed to estimate the loss generated by the devices. In an effort to simplify the design process for engineers, Texas Instruments has provided measured power loss performance curves. Figure 1 plots the power loss of the CSD87588N as a function of load current. This curve is measured by configuring and running the CSD87588N as it would be in the final application (see Figure 27). The measured power loss is the CSD87588N loss and consists of both input conversion loss and gate drive loss. Equation 1 is used to generate the power loss curve.

$$(V_{IN} \times I_{IN}) + (V_{DD} \times I_{DD}) - (V_{SW AVG} \times I_{OUT}) = Power Loss$$

$$(1)$$

The power loss curve in Figure 1 is measured at the maximum recommended junction temperatures of 125°C under isothermal test conditions.

# **Safe Operating Curves (SOA)**

The SOA curves in the CSD87588N data sheet provides guidance on the temperature boundaries within an operating system by incorporating the thermal resistance and system power loss. Figure 3 to Figure 4 outline the temperature and airflow conditions required for a given load current. The area under the curve dictates the safe operating area. All the curves are based on measurements made on a PCB design with dimensions of 4" (W) x 3.5" (L) x 0.062" (T) and 6 copper layers of 1 oz. copper thickness.

#### **Normalized Curves**

The normalized curves in the CSD87588N data sheet provides guidance on the Power Loss and SOA adjustments based on their application specific needs. These curves show how the power loss and SOA boundaries will adjust for a given set of systems conditions. The primary Y-axis is the normalized change in power loss and the secondary Y-axis is the change is system temperature required in order to comply with the SOA curve. The change in power loss is a multiplier for the Power Loss curve and the change in temperature is subtracted from the SOA curve.

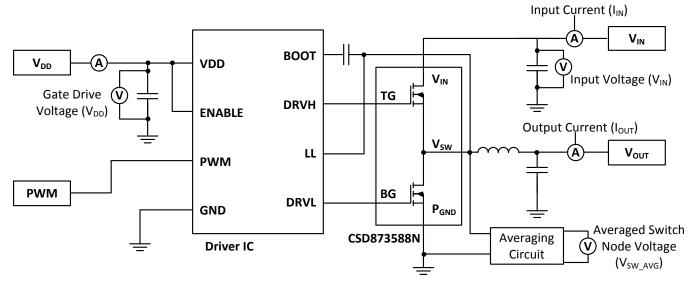


Figure 27. Typical Application



#### Calculating Power Loss and SOA

The user can estimate product loss and SOA boundaries by arithmetic means (see Design Example). Though the Power Loss and SOA curves in this data sheet are taken for a specific set of test conditions, the following procedure will outline the steps the user should take to predict product performance for any set of system conditions.

## **Design Example**

**Operating Conditions:** 

- Output Current = 15A
- Input Voltage = 7V
- Output Voltage = 1V
- Switching Frequency = 800kHz
- Inductor = 0.2µH

#### **Calculating Power Loss**

- Power Loss at 15A = 2.75W (Figure 1)
- Normalized Power Loss for input voltage ≈ 1.03 (Figure 6)
- Normalized Power Loss for output voltage ≈ 0.94 (Figure 7)
- Normalized Power Loss for switching frequency ≈ 1.08 (Figure 5)
- Normalized Power Loss for output inductor ≈ 1.03 (Figure 8)
- Final calculated Power Loss = 2.75W x 1.05 x 0.95 x 1.05 x 1.05 ≈ 3.02W

#### **Calculating SOA Adjustments**

- SOA adjustment for input voltage ≈ 0.3°C (Figure 6)
- SOA adjustment for output voltage ≈ -0.5°C (Figure 7)
- SOA adjustment for switching frequency ≈ 0.7°C (Figure 5)
- SOA adjustment for output inductor ≈ 0.3°C (Figure 8)
- Final calculated SOA adjustment =  $0.3 + (-0.5) + 0.7 + 0.3 \approx 0.8$ °C

In the design example above, the estimated power loss of the CSD87588N would increase to 3.02W. In addition, the maximum allowable board and/or ambient temperature would have to decrease by 0.8°C. Figure 28 graphically shows how the SOA curve would be adjusted accordingly.

- 1. Start by drawing a horizontal line from the application current to the SOA curve.
- 2. Draw a vertical line from the SOA curve intercept down to the board/ambient temperature.
- 3. Adjust the SOA board/ambient temperature by subtracting the temperature adjustment value.

In the design example, the SOA temperature adjustment yields a reduction in allowable board/ambient temperature of 0.8°C. In the event the adjustment value is a negative number, subtracting the negative number would yield an increase in allowable board/ambient temperature.

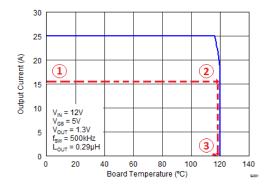


Figure 28. Power Block SOA



#### RECOMMENDED PCB DESIGN OVERVIEW

There are two key system-level parameters that can be addressed with a proper PCB design: Electrical and Thermal performance. Properly optimizing the PCB layout will yield maximum performance in both areas. A brief description on how to address each parameter is provided.

#### **Electrical Performance**

The CSD87588N has the ability to switch voltages at rates greater than 10kV/µs. Special care must be then taken with the PCB layout design and placement of the input capacitors, inductor, and output capacitors.

- The placement of the input capacitors relative to VIN and PGND pins of CSD87588N device should have the highest priority during the component placement routine. It is critical to minimize these node lengths. As such, ceramic input capacitors need to be placed as close as possible to the VIN and PGND pins (see Figure 5). The example in Figure 5 uses 1x10nF 0402 25V and 4 x 10µF 1206 25V ceramic capacitors (TDK Part # C3216X5R1C106KT or equivalent). Notice there are ceramic capacitors on both sides of the board with an appropriate amount of vias interconnecting both layers. In terms of priority of placement next to the Power Stage C21, C5, C8, C19, and C18 should follow in order.
- The switching node of the output inductor should be placed relatively close to the Power Block II CSD87588N VSW pins. Minimizing the VSW node length between these two components will reduce the PCB conduction losses and actually reduce the switching noise level.see Figure 29 (1)
- Keong W. Kam, David Pommerenke, "EMI Analysis Methods for Synchronous Buck Converter EMI Root Cause Analysis", University of Missouri – Rolla

#### **Thermal Performance**

The CSD87588N has the ability to utilize the PGND planes as the primary thermal path. As such, the use of thermal vias is an effective way to pull away heat from the device and into the system board. Concerns of solder voids and manufacturability problems can be addressed by the use of three basic tactics to minimize the amount of solder attach that will wick down the via barrel:

- Intentionally space out the vias from each other to avoid a cluster of holes in a given area.
- Use the smallest drill size allowed in your design. The example in Figure 29 uses vias with a 10 mil drill hole and a 16 mil capture pad.
- Tent the opposite side of the via with solder-mask.

In the end, the number and drill size of the thermal vias should align with the end user's PCB design rules and manufacturing capabilities.

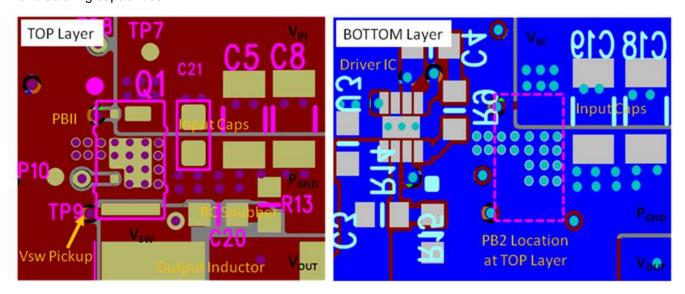
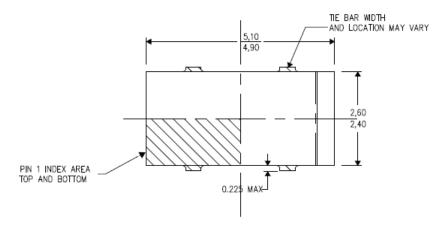


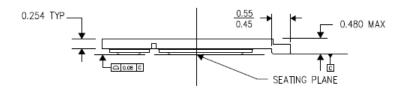
Figure 29. Recommended PCB Layout (Top Down View)

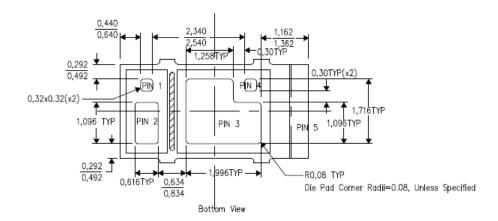


#### **MECHANICAL DATA**

# **CSD87588N Package Dimensions**





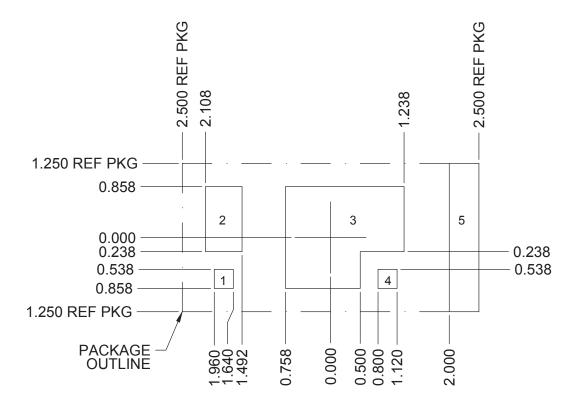


**Table 1. Pin Configuration** 

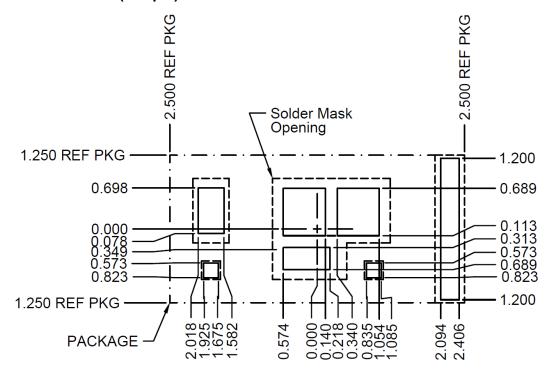
Position	Designation
Pin 1	TG
Pin 2	V <sub>IN</sub>
Pin 3	$P_{GND}$
Pin 4	BG
Pin 5	$V_{SW}$



#### **Land Pattern Recommendation**

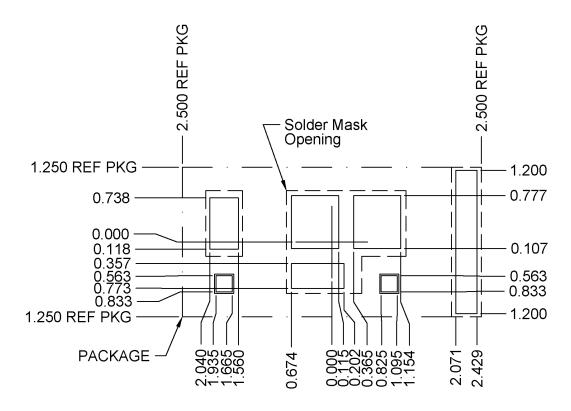


# Stencil Recommendation (100 µm)





# Stencil Recommendation (125 µm)



For recommended circuit layout for PCB designs, see application note SLPA005 – Reducing Ringing Through PCB Layout Techniques.

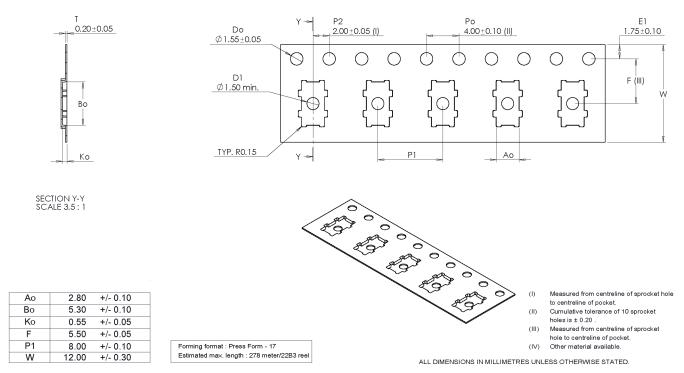
# **Pin Drawing**

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# **CSD87588N Embossed Carrier Tape Dimensions**



(1) Pin 1 will be oriented in the top left quadrant of the tape enclosure (closest to the carrier tape sprocket holes).

#### **REVISION HISTORY**

# Changes from Original (March 2013) to Revision A Page • Changed R<sub>θJC-PCB</sub>To: R<sub>θJC</sub> in the THERMAL INFORMATION table 3



# PACKAGE OPTION ADDENDUM

16-Apr-2013

#### **PACKAGING INFORMATION**

Orderable Device	Status	Package Type	_	Pins	U	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Top-Side Markings	Samples
	(1)		Drawing		Qty	(2)		(3)		(4)	
CSD87588N	ACTIVE	PTAB	MPA	5	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 150	87588N	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

**Pb-Free** (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes. **Pb-Free** (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) Multiple Top-Side Markings will be inside parentheses. Only one Top-Side Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Top-Side Marking for that device.

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